ABSTRACT OF THE DISCLOSURE

A testing card including a converting circuit, a latch circuit, a data processor, a signal generator, an oscillation combination circuit, and a reset circuit is provided. The converting circuit is used to receive the attribute control signal, the common memory signal and the input/output signal fed in from the card interface, convert these signals and output them to the data processor afterwards. The latch circuit is used to receive the data signal fed in from the card interface, latch the data signal and output it to the data processor afterwards. Having received the signal sent from the converting circuit and the latch circuit, the data processor will be able to proceed with testing accordingly. The signal generator can output the mode selection signal and the interrupt signal to the card interface to test the functions of mode selection and interrupt signals. Furthermore, the signal generator outputs the enable signal to the oscillation combination circuit according to the control signal fed in from the card interface, so that the oscillation combination circuit can generate a wait signal according to the enable signal and feed the wait signal to the card interface for testing purpose. The reset circuit is used to reset the above latch circuit, data processor, signal generator and oscillation combination circuit to start the testing process again.

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